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ILNAS-EN IEC 62433-6:2020

EMC IC modelling - Part 6: Models of integrated circuits for pulse immunity behavioural simulation - Conducted pulse immunity modelling (ICIM-CPI)

Modèles de circuits intégrés pour la CEM -
Partie 6: Modèles de circuits intégrés
pour la simulation du comportement
d'immunité aux impulsions -

EMV-IC-Modellierung - Teil 6: Modelle
integrierter Schaltungen für die
Simulation des Verhaltens bei
Störfestigkeit gegen Impulse -



National Foreword

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English Version

EMC IC modelling - Part 6: Models of integrated circuits for Pulse immunity behavioural simulation - Conducted Pulse Immunity (ICIM-CPI) (IEC 62433-6:2020)

Modèles de circuits intégrés pour la CEM - Partie 6:
Modèles de circuits intégrés pour la simulation du
comportement d'immunité aux impulsions - Modélisation de
l'immunité aux impulsions conduites (ICIM-CPI)
(IEC 62433-6:2020)

EMV-IC-Modellierung - Teil 6: Modelle integrierter
Schaltungen für die Simulation des Verhaltens bei
Störfestigkeit gegen Impulse - Modellierung der
Störfestigkeit gegen leitungsgeführte Impulse (ICIM-CPI)
(IEC 62433-6:2020)

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

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European foreword

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- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2021-07-27
- latest date by which the national standards conflicting with the document have to be withdrawn (dow) 2023-10-27

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IEC 62433-2:2017	NOTE	Harmonized as EN 62433-2:2017 (not modified)
CISPR 16-1-4:2019	NOTE	Harmonized as EN IEC 55016-1-4:2019 (not modified)
CISPR 17	NOTE	Harmonized as EN 55017

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 Where an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 61000-4-2	-	Electromagnetic compatibility (EMC) - Part 4-2: Testing and measurement techniques - Electrostatic discharge immunity test	EN 61000-4-2	-
IEC 61000-4-4	-	Electromagnetic compatibility (EMC) - Part 4-4: Testing and measurement techniques - Electrical fast transient/burst immunity test	EN 61000-4-4	-
IEC 62215-3	-	Integrated circuits - Measurement of impulse immunity - Part 3: Non-synchronous transient injection method	EN 62215-3	-
IEC 62433-1	-	EMC IC modelling - Part 1: General modelling framework	EN IEC 62433-1	-
IEC 62433-4	-	EMC IC modelling - Part 4: Models of integrated circuits for RF immunity behavioural simulation - Conducted immunity modelling (ICIM-CI)	EN 62433-4	-
IEC 62615	-	Electrostatic discharge sensitivity testing - Transmission line pulse (TLP) - Component level	-	-



INTERNATIONAL STANDARD

NORME INTERNATIONALE



EMC IC modelling –

**Part 6: Models of integrated circuits for pulse immunity behavioural simulation –
Conducted pulse immunity modelling (ICIM-CPI)**

Modèles de circuits intégrés pour la CEM –

**Partie 6: Modèles de circuits intégrés pour la simulation du comportement
d'immunité aux impulsions – Modélisation de l'immunité aux impulsions
conduites (ICIM-CPI)**

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